



DOCUMENT CHANGE REQUEST

DCR number 211 Changes required for: General
Date: 2005/11/17 Date sent: 2005/11/17
Status: IMPLEMENTED

Originator: John Wong
Organisation: ESA/ESTEC

Title: Generic Specification for Discrete Semiconductor Components

Number: 5000 Issue: 2

Other documents affected:

Page:

8.7 Particle Impact Noise Detection (PIND)

Paragraph:

8.7 Particle Impact Noise Detection (PIND)

Original wording:

Proposed wording:


Re-instate wording per ESA/SCC Generic Specification No. 5000, Issue 9, Revision A, paragraph 9.7

Justification:

Test Method 2052 of MIL-STD-750 is the same as Test Method 2020 of MIL-STD-883 except that paragraph 3.5 of Test Method 2020 providing prescriptions for testing is missing from Test Method 2052.

In Test Method 2052 the user must refer to MIL-PRF-19500 Appendix E.5.4.1 to find the same prescriptions for JAN S devices.

The paragraph as stated in ESA/SCC Generic Specification No. 5000, Issue 9, Revision A correctly defines the prescriptions.

Attachments:
N/A
Modifications:
N/A
Approval signature:

Date signed:
2005-11-17